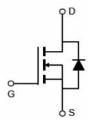
Main Product Characteristics:

V _{DSS}	100V
R _{DS} (on)	4.2mΩ (typ.)
I _D	160A







TO-220 SSS1004L

TO-263 SSS1004AL

Schematic Diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute Max Rating:

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V①	160	^
I _{DM}	Pulsed Drain Current②	600	- A
P _D @T _C = 25°C	Power Dissipation③	225	W
V _{DS}	Drain-Source Voltage	100	V
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy @ L=0.1mH	320	mJ
I _{AS}	Avalanche Current	80	Α
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C



Thermal Resistance

Symbol	Characteristics	Тур.	Max.	Units
R _{θJC}	Junction-to-case ③	_	62	°
R _{θJA}	Junction-to-ambient ④	_	0.55	°C/W

$\textbf{Electrical Characteristics} @ \textbf{T}_{A} = 25 \, ^{\circ} \textbf{Cunless otherwise specified}$

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	100	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
R _{DS(on)}	Static Drain-to-Source on-resistance	_	4.2	4.8	mΩ	Vgs=10V, ID=30A
V _{GS(th)}	Gate threshold voltage	2.5	_	4.2	V	V _{DS} =V _{GS} ,I _D =250uA
I _{DSS}	Drain-to-Source leakage current T _j =25°C	_	_	1	μA	V _{DS} =100V,V _{GS} =0V,
Land	Cata to Source forward lookege	_	_	100	nA	Vgs=20V,Vps=0V
I _{GSS}	Gate-to-Source forward leakage			-100	IIA	Vgs=-20V,Vps=0V
gfs	Transconductance	_	100	_	S	V _{DS} =5V,I _D =30A
Qg	Total gate charge	_	78	_		
Q _{gs}	Gate-to-Source charge	_	32	_	nC	Tj=25°C, Vgs=10V, Vps=50V,lp=80A
Q _{gd}	Gate-to-Drain("Miller") charge	_	17	_		VDS-30 V,ID-00A
t _{d(on)}	Turn-on delay time	_	28.4	_		V _G s=10V
t _r	Rise time	_	39.2	_		V _{DS} =50V
t _{d(off)}	Turn-Off delay time	_	53.6	_	ns	ID=80A
t _f	Fall time	_	32.8	_		$R_G=5\Omega$
C _{iss}	Input capacitance	_	3950	_		V _G s=0V
Coss	Output capacitance		1200	_	pF	V _{DS} =50V
C _{rss}	Reverse transfer capacitance		45	_		f=1MHz

Source-Drain Ratings and Characteristics

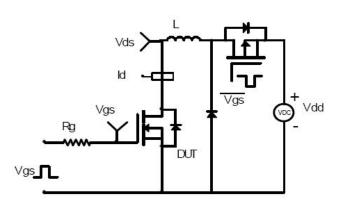
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1.	Continuous Source Current			160		MOSFET symbol
Is	(Body Diode)	_	_	160	A	showing the
	Pulsed Source Current			600	^	integral reverse
I _{SM}	(Body Diode)	_	_	600	A	p-n junction diode.
V _{SD}	Diode Forward Voltage	_	_	1.2	V	I _S =10A, V _{GS} =0V
trr	Reverse Recovery Time	_	82	_	ns	I204 d1/dt-5004/up
Qrr	Reverse Recovery Charge	_	180	_	nC	- I _F =20A, dI/dt=500A/μs



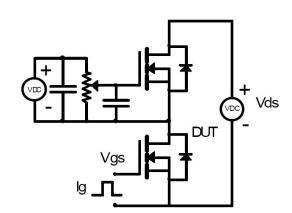


Test Circuits and Waveforms

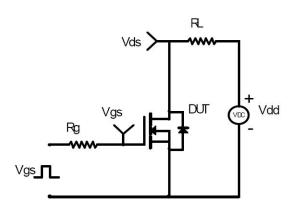
EAS Test Circuit:



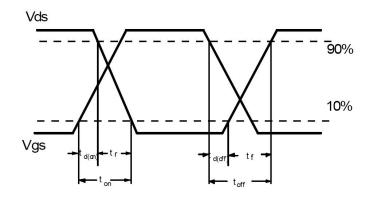
Gate Charge Test Circuit:



Switching Time Test Circuit:



Switching Waveforms:



Version: 1.2

Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4 The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C.



Typical Electrical and Thermal Characteristics

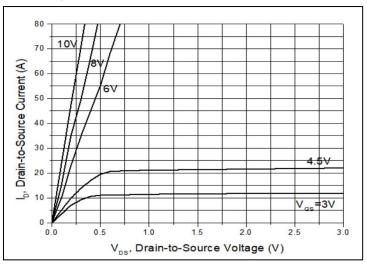


Figure 1. Output Characteristics

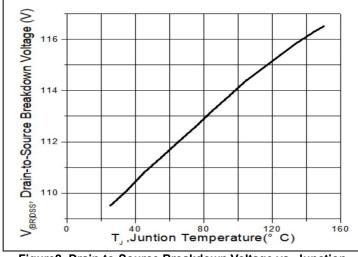


Figure2. Drain-to-Source Breakdown Voltage vs. Junction

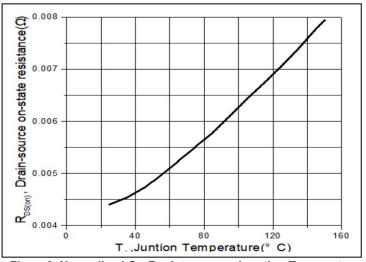


Figure 3. Normalized On-Resistance vs. Junction Temperature

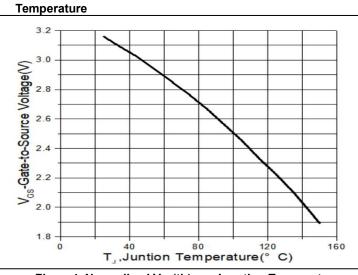


Figure 4. Normalized V_{GS}(th) vs. Junction Temperature

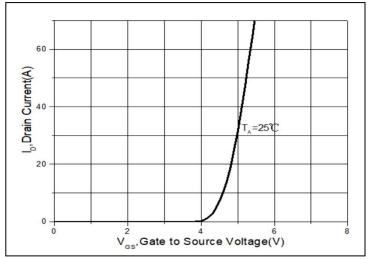


Figure 5. Transfer Characteristics

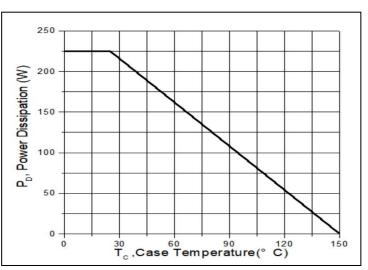


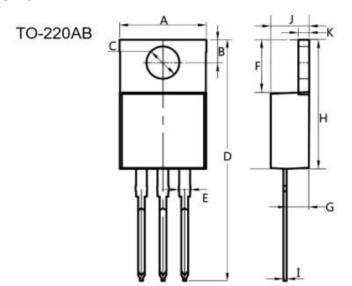
Figure 6. Power Dissipation



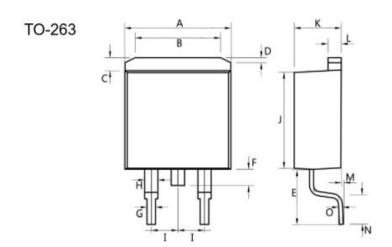
Mechanical Data:

Product ID	Pack
SSS1004L	TO-220
SSS1004AL	TO-263

Unit:mm



Min.	Max.
10.0	10.4
2.5	3.0
3.5	4.0
28.0	30.0
1.1	1.5
6.2	6.6
2.9	3.3
15.0	16.0
0.35	0.45
4.3	4.7
1.2	1.4
	2.5 3.5 28.0 1.1 6.2 2.9 15.0 0.35 4.3



Dim.	Min.	Max.
Α	10.0	10. 5
В	7.25	7.75
С	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
Н	1.15	1.35
1	Тур	2.54
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
М	0.02	0.1
N	2.4	2.8
0	0.35	0.45



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